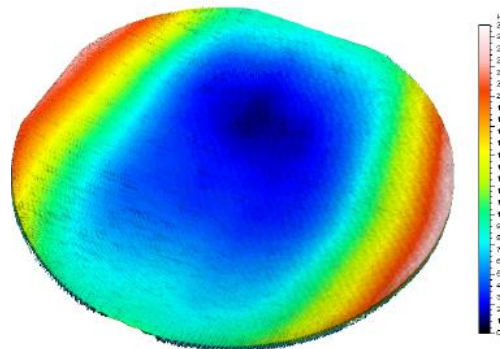
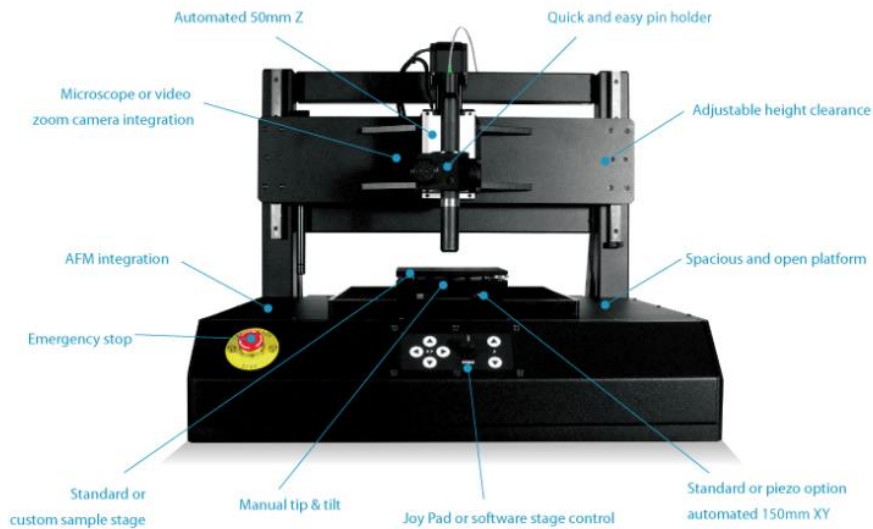


# Profilometers



## Applications:

- Silicon wafer flatness
- Transparent film on transparent substrate
- Thin film thickness 3D Profilometry
- Solar cell inspection

## Features:

- 150mm X-Y stages with adjustable height up to 200mm,
- Sub nanometer range with optical video zoom and AFM integration
- Quality control options

## Benefits:

- High speed profiling due to chromatic confocal line sensors
- 3D graphics and auto video scan
- Wide range of samples with varying geometries
- High magnification microscopy combined with other properties
- Custom configurations